74LVT574; 74LVTH574

3.3 V octal D-type flip-flop; 3-state
Rev. 7 — 22 November 2011

Product data sheet

General description 1.

The 74LVT574; 74LVTH574 is a high-performance product designed for V_{CC} operation at 3.3 V.

This device is an 8-bit, edge triggered register coupled to eight 3-state output buffers. The two sections of the device are controlled independently by the clock (pin CP) and output enable (pin OE) control gates. The state of each Dn input (one setup time before the LOW-to-HIGH clock transition) is transferred to the corresponding flip-flops Qn output.

The 3-state output buffers are designed to drive heavily loaded 3-state buses, MOS memories, or MOS microprocessors.

The active LOW output enable (pin OE) controls all eight 3-state buffers independent of the clock operation.

When pin OE is LOW, the stored data appears at the outputs. When pin OE is HIGH, the outputs are in the high-impedance OFF-state, which means they will neither drive nor load the bus.

2. Features and benefits

- Inputs and outputs arranged for easy interfacing to microprocessors
- 3-state outputs for bus interfacing
- Common output enable control
- TTL input and output switching levels
- Input and output interface capability to systems at 5 V supply
- Bus hold data inputs eliminate need for external pull-up resistors to hold unused inputs
- Live insertion and extraction permitted
- No bus current loading when output is tied to 5 V bus
- Power-up reset
- Power-up 3-state
- Latch-up protection
 - JESD78 class II exceeds 500 mA
- ESD protection:
 - HBM JESD22-A114E exceeds 2000 V
 - MM JESD22-A115-A exceeds 200 V
- Specified from -40 °C to +85 °C

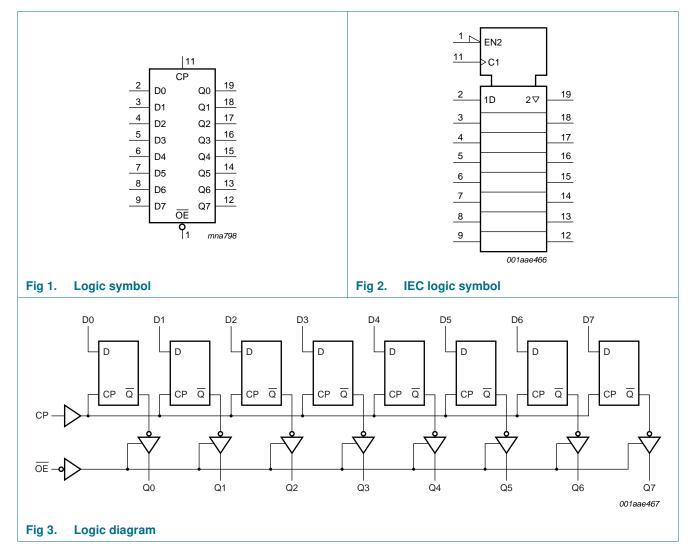


3. Ordering information

Table 1. Ordering information

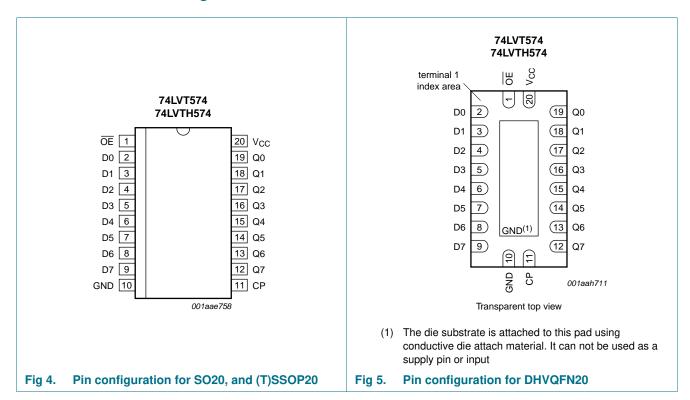
Type number	Package				
	Temperature range	Name	Description	Version	
74LVT574D	–40 °C to +85 °C	SO20	plastic small outline package; 20 leads;	SOT163-1	
74LVTH574D			body width 7.5 mm		
74LVT574DB	pidolio cilinini cili		plastic shrink small outline package; 20 leads;	SOT339-1	
74LVTH574DB			body width 5.3 mm		
74LVT574PW	–40 °C to +85 °C	TSSOP20	plastic thin shrink small outline package; 20 leads;	SOT360-1	
74LVTH574PW			body width 4.4 mm		
74LVT574BQ	574BQ $-40~^{\circ}\text{C}$ to $+85~^{\circ}\text{C}$ DHVQFN20 plastic dual in-line compatible thermal enhanced very thin quad flat package; no leads; 20 terminals; body $2.5 \times 4.5 \times 0.85~\text{mm}$				

4. Functional diagram



5. Pinning information

5.1 Pinning



5.2 Pin description

Table 2. Pin description

Symbol	Pin	Description
ŌĒ	1	output enable input (active LOW)
D0 to D7	2, 3, 4, 5, 6, 7, 8, 9	data input
GND	10	ground (0 V)
СР	11	clock pulse input (active rising edge)
Q0 to Q7	19, 18, 17, 16, 15, 14, 13, 12	data output
V _{CC}	20	supply voltage

6. Functional description

6.1 Function table

Table 3. Function table [1]

Operating mode	Control		Input	Internal register	Output
	OE	СР	Dn		Qn
Load and read register	L	↑	I	L	L
			h	Н	Н
Hold	L	NC	Χ	NC	NC
Disable outputs	Н	L or H	X	NC	Z
		\uparrow	Dn	Dn	Z

^[1] H = HIGH voltage level;

h = HIGH voltage level one setup time prior to the LOW-to-HIGH clock transition;

NC = no change;

X = don't care.

7. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134). Voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions	Min	Max	Unit
V_{CC}	supply voltage		-0.5	+4.6	V
VI	input voltage		<u>[1]</u> –0.5	+7.0	V
V _O	output voltage	output in OFF-state or HIGH-state	<u>[1]</u> –0.5	+7.0	V
I _{IK}	input clamping current	$V_I < 0 V$	-	-50	mA
I _{OK}	output clamping current	V _O < 0 V	-	-50	mA
I_{O}	output current	output in LOW-state	-	128	mA
		output in HIGH-state	-	-64	mA
T _{stg}	storage temperature		-65	+150	°C
Tj	junction temperature		[2] _	150	°C
P _{tot}	total power dissipation	$T_{amb} = -40 ^{\circ}\text{C} \text{ to } +85 ^{\circ}\text{C}$	<u>[3]</u> _	500	mW

^[1] The input and output negative voltage ratings may be exceeded if the input and output clamp current ratings are observed.

L = LOW voltage level;

^{↑ =} LOW-to-HIGH clock transition;

I = LOW voltage level one setup time prior to the LOW-to-HIGH clock transition;

Z = high-impedance OFF-state;

^[2] The performance capability of a high-performance integrated circuit in conjunction with its thermal environment can create junction temperatures which are detrimental to reliability.

^[3] For SO20 packages: above 70 °C derate linearly with 8 mW/K.
For SSOP20 and TSSOP20 packages: above 60 °C derate linearly with 5.5 mW/K.
For DHVQFN20 packages: above 60 °C derate linearly with 4.5 mW/K.

8. Recommended operating conditions

Table 5. Recommended operating conditions

Symbol	Parameter	Conditions	Min	Max	Unit
V_{CC}	supply voltage		2.7	3.6	V
VI	input voltage		0	5.5	V
V_{IH}	HIGH-level input voltage		2.0	-	V
V_{IL}	LOW-level input voltage		-	8.0	V
I _{OH}	HIGH-level output current		-	-32	mA
I _{OL}	LOW-level output current		-	32	mA
		current duty cycle ≤ 50 %; $f_i \geq 1~kHz$	-	64	mA
T _{amb}	ambient temperature	in free air	-40	+85	°C
$\Delta t/\Delta V$	input transition rise and fall rate	outputs enabled	-	10	ns/V

9. Static characteristics

Table 6. Static characteristics

At recommended operating conditions; voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions		T _{amb} =	–40 °C to +	85 °C	Unit
				Min	Typ[1]	Max	
V_{IK}	input clamping voltage	$V_{CC} = 2.7 \text{ V}; I_{IK} = -18 \text{ mA}$		-1.2	-0.9	-	V
V_{OH}	HIGH-level output voltage	V_{CC} = 2.7 V to 3.6 V; I_{OH} = $-100~\mu A$		V _{CC} – 0.2	$V_{CC}-0.1$	-	V
		$V_{CC} = 2.7 \text{ V}; I_{OH} = -8 \text{ mA}$		2.4	2.5	-	V
		$V_{CC} = 3.0 \text{ V}; I_{OH} = -32 \text{ mA}$		2.0	2.2	-	V
V _{OL}	LOW-level output voltage	V _{CC} = 2.7 V					
		I _{OL} = 100 μA		-	0.1	0.2	V
		I _{OL} = 24 mA		-	0.3	0.5	V
		V _{CC} = 3.0 V					
		I _{OL} = 16 mA		-	0.25	0.4	V
		I _{OL} = 32 mA		-	0.3	0.5	V
		I _{OL} = 64 mA		-	0.4	0.55	V
$V_{OL(pu)}$	power-up LOW-level output voltage	V_{CC} = 3.6 V; I_{O} = 1 mA; V_{I} = GND or V_{CC}	[2]	-	0.13	0.55	V
I _I	input leakage current	all input pins; $V_{CC} = 0 \text{ V or } 3.6 \text{ V}; V_I = 5.5 \text{ V}$		-	1	10	μΑ
		control pins; V _{CC} = 3.6 V; V _I = V _{CC} or GND		-	±0.1	±1	μΑ
		data pins; V _{CC} = 3.6 V	[3]				
		$V_I = V_{CC}$		-	0.1	1	μΑ
		V _I = 0 V		-5	-1	-	μΑ
I _{OFF}	power-off leakage current	$V_{CC} = 0 \text{ V}$; $V_I \text{ or } V_O = 0 \text{ V to } 4.5 \text{ V}$		-	1	±100	μΑ
I _{LO}	output leakage current	V_O = 5.5 V and V_{CC} = 3.0 V; output HIGH	[4]	-	60	125	μΑ
I _{BHL}	bus hold LOW current	$V_{CC} = 3.0 \text{ V}; V_I = 0.8 \text{ V}$		75	150	-	μΑ
I _{BHH}	bus hold HIGH current	$V_{CC} = 3.0 \text{ V}; V_I = 2.0 \text{ V}$	<u>[4]</u>	-	-150	-75	μΑ
I _{BHHO}	bus hold HIGH overdrive current	$V_{CC} = 3.6 \text{ V}; V_I = 0 \text{ V to } 3.6 \text{ V}$	[4]	-	-	500	μА

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Table 6. Static characteristics ...continued

At recommended operating conditions; voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions		T _{amb} =	–40 °C to +	-85 °C	Unit
				Min	Typ[1]	Max	
I _{BHLO}	bus hold LOW overdrive current	$V_{CC} = 3.6 \text{ V}; V_I = 0 \text{ V to } 3.6 \text{ V}$	'	-500	-	-	μΑ
I _{O(pu/pd)}	power-up/power-down output current	$V_{CC} \le 1.2 \text{ V}; V_O = \underline{0.5} \text{ V to } V_{CC};$ $V_I = \text{GND or } V_{CC}; \overline{OE} = \text{don't care}$	[5]	-	1	±100	μА
l _{OZ}	OFF-state output current	$V_{CC} = 3.6 \text{ V}; V_I = V_{IH} \text{ or } V_{IL}$					
		output HIGH: V _O = 3.0 V		-	1	5	μΑ
		output LOW: V _O = 0.5 V		-5	1	-	μΑ
I _{CC}	supply current	V_{CC} = 3.6 V; V_I = GND or V_{CC} ; I_O = 0 A					
		outputs HIGH		-	0.13	0.19	mΑ
		outputs LOW		-	3	12	mA
		outputs disabled	[6]	-	0.13	0.19	mA
ΔI_{CC}	additional supply current	per input pin; V_{CC} = 3 V to 3.6 V; one input at V_{CC} – 0.6 V and other inputs at V_{CC} or GND	[7]	-	0.1	0.2	mA
Cı	input capacitance	$V_1 = 0 \ V \ or \ 3.0 \ V$		-	4	-	pF
Co	output capacitance	outputs disabled; $V_O = 0 \text{ V}$ or 3.0 V		-	8	-	pF

^[1] Typical values are measured at V_{CC} = 3.3 V and T_{amb} = 25 °C.

10. Dynamic characteristics

Table 7. Dynamic characteristics

Voltages are referenced to ground (GND = 0 V); for test circuit see Figure 10.

Symbol	Parameter	Conditions		-40 °C to	+85 °C	Unit
			Min	Typ[1]	Max	
t_{PLH}	LOW to HIGH propagation delay	CP to Qn; see Table 6				
		$V_{CC} = 3.0 \text{ V to } 3.6 \text{ V}$	1.7	3.6	5.4	ns
		$V_{CC} = 2.7 \text{ V}$	-	-	6.2	ns
t _{PHL}	HIGH to LOW propagation delay	CP to Qn; see <u>Table 6</u>				
		$V_{CC} = 3.0 \text{ V to } 3.6 \text{ V}$	2.4	4.3	5.9	ns
		$V_{CC} = 2.7 \text{ V}$	-	-	6.6	ns
t_{PZH}	OFF-state to HIGH propagation delay	OE to Qn; see Figure 7				
		$V_{CC} = 3.0 \text{ V to } 3.6 \text{ V}$	1.0	2.9	4.8	ns
		$V_{CC} = 2.7 \text{ V}$	-	-	5.9	ns

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^[2] For valid test results, data must not be loaded into the flip-flops (or latches) after applying power.

^[3] Unused pins at V_{CC} or GND.

^[4] This is the bus hold overdrive current required to force the input to the opposite logic state.

^[5] This parameter is valid for any V_{CC} between 0 V and 1.2 V with a transition time of up to 10 ms. From V_{CC} = 1.2 V to V_{CC} = 3.3 V \pm 0.3 V a transition time of 100 μ s is permitted. This parameter is valid for T_{amb} = 25 °C only.

^[6] I_{CC} is measured with outputs pulled to V_{CC} or GND.

^[7] This is the increase in supply current for each input at the specified voltage level other than V_{CC} or GND.

 Table 7.
 Dynamic characteristics ...continued

Voltages are referenced to ground (GND = 0 V); for test circuit see Figure 10.

Symbol	Parameter	Conditions		T _{amb} =	–40 °C to	+85 °C	Unit
				Min	Typ[1]	Max	
t_{PZL}	OFF-state to LOW propagation delay	OE to Qn; see Figure 8			'		
		V _{CC} = 3.0 V to 3.6 V		1.3	3.4	5.1	ns
		V _{CC} = 2.7 V		-	-	6.2	ns
t _{PHZ}	HIGH to OFF-state propagation delay	OE to Qn; see Figure 7					
		V _{CC} = 3.0 V to 3.6 V		1.9	4.0	5.5	ns
		V _{CC} = 2.7 V		-	-	5.9	ns
t _{PLZ}	LOW to OFF-state propagation delay	OE to Qn; see Figure 8					
		V _{CC} = 3.0 V to 3.6 V		1.7	3.2	4.5	ns
		V _{CC} = 2.7 V		-	-	4.5	ns
t _{su}	set-up time	Dn to CP; see Figure 9	[2]				
		V _{CC} = 3.0 V to 3.6 V		2.0	-	-	ns
		V _{CC} = 2.7 V		2.4	-	-	ns
t _h	hold time	Dn to CP; see Figure 9	[3]				
		V _{CC} = 3.0 V to 3.6 V		0.3	-	-	ns
		$V_{CC} = 2.7 \text{ V}$		0	-	-	ns
t _W	pulse width	CP input; see Figure 6	[4]				
		$V_{CC} = 3.0 \text{ V to } 3.6 \text{ V}$		3.3	-	-	ns
		V _{CC} = 2.7 V		3.3	-	-	ns
f _{max}	maximum frequency	CP input; $V_{CC} = 3.0 \text{ V}$ to 3.6 V; see Figure 6		150	-	-	MHz

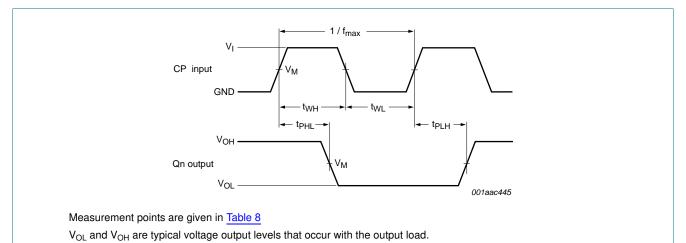
^[1] Typical values are at V_{CC} = 3.3 V and T_{amb} = 25 °C.

^[2] $\quad t_{su}$ is the same as $t_{su(H)}$ and $t_{su(L)}$

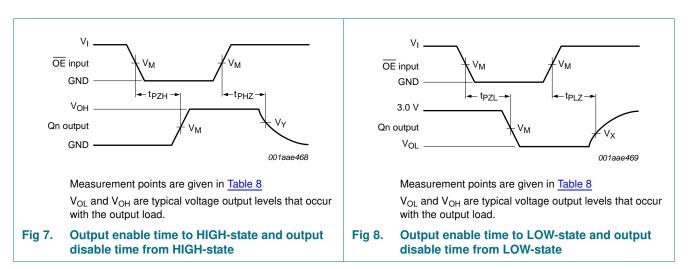
^[3] t_h is the same as $t_{h(H)}$ and $t_{h(L)}$

^[4] $\ t_W$ is the same as t_{WH} and t_{WL}

11. Waveforms



Propagation delay clock input (CP) to output (Qn), pulse width clock (CP) and maximum clock frequency Fig 6.

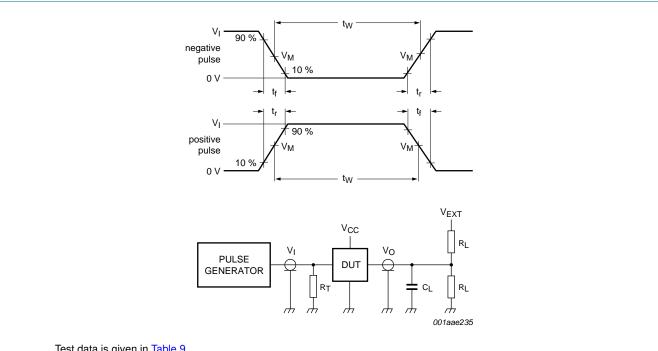


Dn input **GND** t_{h(H)} t_{su(L)} t_{h(L)} t_{su(H)} CP input ٧_M ٧_M GND 001aac738 Measurement points are given in Table 8 Remark: The shaded areas indicate when the input is permitted to change for predictable output performance.

Fig 9. Data setup and hold times

Table 8. **Measurement points**

Input	Output		
V_{M}	V _M	V _X	V _Y
1.5 V	1.5 V	V _{OL} + 0.3 V	V _{OH} – 0.3 V



Test data is given in Table 9.

Definitions test circuit:

R_I = Load resistance.

 C_L = Load capacitance including jig and probe capacitance.

 R_T = Termination resistance should be equal to output impedance Z_o of the pulse generator.

 V_{EXT} = Test voltage for switching times.

Fig 10. Load circuitry for switching times

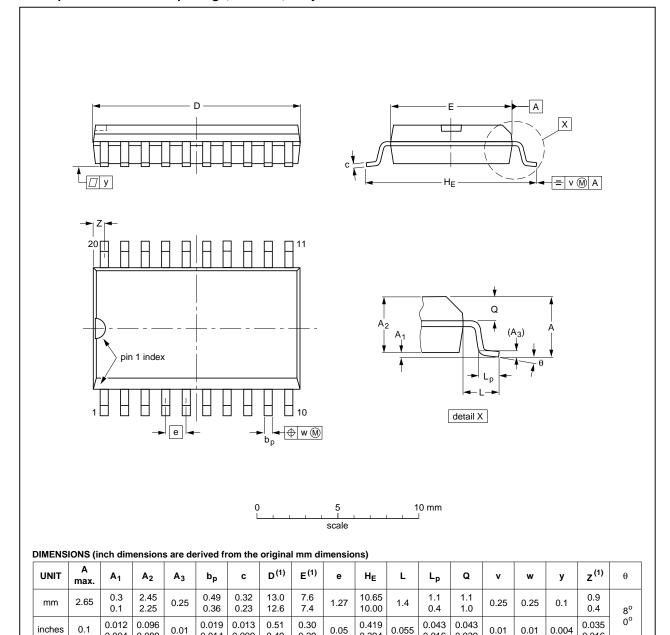
Table 9. **Test data**

Input			Load		V _{EXT}			
V_{I}	f _i	t _W	t _r , t _f	t _f C _L R _L		t_{PHZ} , t_{PZH}	t_{PLZ} , t_{PZL}	t _{PLH} , t _{PHL}
2.7 V	\leq 10 MHz	500 ns	\leq 2.5 ns	50 pF	500Ω	GND	6 V	open

12. Package outline

SO20: plastic small outline package; 20 leads; body width 7.5 mm

SOT163-1



Note

1. Plastic or metal protrusions of 0.15 mm (0.006 inch) maximum per side are not included.

0.014

0.009

OUTLINE		REFER	ENCES	EUROPEAN	ISSUE DATE
VERSION	IEC	JEDEC	JEITA	PROJECTION	ISSUE DATE
SOT163-1	075E04	MS-013			99-12-27 03-02-19

0.394

0.016

Fig 11. Package outline SOT163-1 (SO20)

0.004

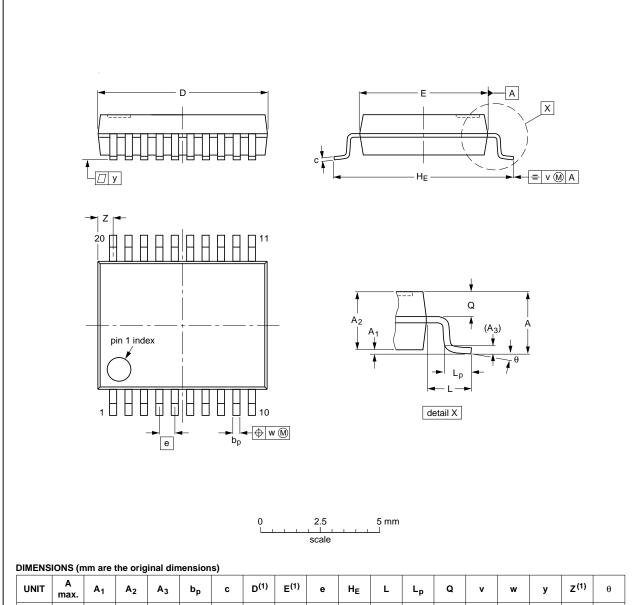
0.089

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SSOP20: plastic shrink small outline package; 20 leads; body width 5.3 mm

SOT339-1



				,		-,												
UNIT	A max.	A ₁	A ₂	A ₃	bp	С	D ⁽¹⁾	E ⁽¹⁾	е	HE	L	Lp	Q	v	w	у	Z ⁽¹⁾	θ
mm	2	0.21 0.05	1.80 1.65	0.25	0.38 0.25	0.20 0.09	7.4 7.0	5.4 5.2	0.65	7.9 7.6	1.25	1.03 0.63	0.9 0.7	0.2	0.13	0.1	0.9 0.5	8° 0°

Note

1. Plastic or metal protrusions of 0.2 mm maximum per side are not included.

OUTLINE		REFER	ENCES	EUROPEAN	ISSUE DATE		
VERSION	IEC	JEDEC	JEITA	PROJECTION	ISSUE DATE		
SOT339-1		MO-150			99-12-27 03-02-19		
						٠	

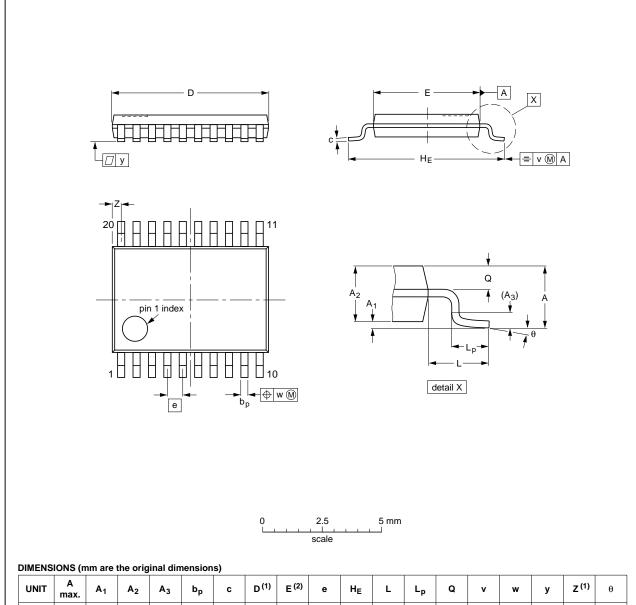
Fig 12. Package outline SOT339-1 (SSOP20)

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TSSOP20: plastic thin shrink small outline package; 20 leads; body width 4.4 mm

SOT360-1



UNIT	A max.	A ₁	A ₂	A ₃	bp	С	D ⁽¹⁾	E ⁽²⁾	e	HE	L	Lp	Q	٧	w	у	Z ⁽¹⁾	θ
mm	1.1	0.15 0.05	0.95 0.80	0.25	0.30 0.19	0.2 0.1	6.6 6.4	4.5 4.3	0.65	6.6 6.2	1	0.75 0.50	0.4 0.3	0.2	0.13	0.1	0.5 0.2	8° 0°

- 1. Plastic or metal protrusions of 0.15 mm maximum per side are not included.
- 2. Plastic interlead protrusions of 0.25 mm maximum per side are not included.

OUTLINE		REFER	ENCES	EUROPEAN	ISSUE DATE		
VERSION	IEC	JEDEC	JEITA	PROJECTION	ISSUE DATE		
SOT360-1		MO-153			99-12-27 03-02-19		
				1	03-02-19		

Fig 13. Package outline SOT360-1 (TSSOP20)

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DHVQFN20: plastic dual in-line compatible thermal enhanced very thin quad flat package; no leads; 20 terminals; body 2.5 x 4.5 x 0.85 mm SOT764-1

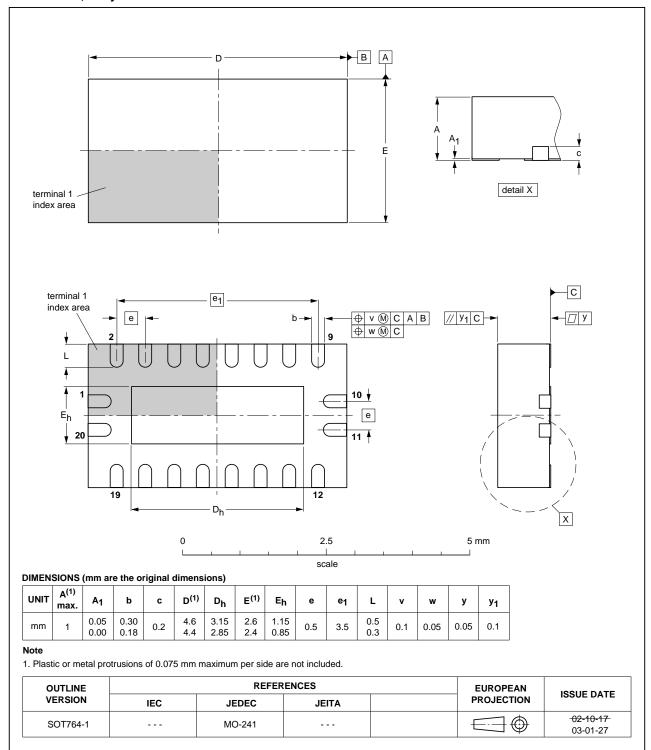


Fig 14. Package outline SOT764-1 (DHVQFN20)

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13. Abbreviations

Table 10. Abbreviations

Acronym	Description
DUT	Device Under Test
ESD	ElectroStatic Discharge
НВМ	Human Body Model
MM	Machine Model
MOS	Metal Oxide Semiconductor
TTL	Transistor-Transistor Logic

14. Revision history

Table 11. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
74LVT_LVTH574 v.7	20111122	Product data sheet	-	74LVT_LVTH574 v.6
Modifications:	 Legal pages 	s updated.		
74LVT_LVTH574 v.6	20110912	Product data sheet	-	74LVT_LVTH574 v.5
74LVT_LVTH574 v.5	20110727	Product data sheet	-	74LVT_LVTH574 v.4
74LVT_LVTH574 v.4	20080911	Product data sheet	-	74LVT_LVTH574 v.3
74LVT_LVTH574 v.3	20060323	Product data sheet	-	74LVT574 v.2
74LVT574 v.2	19980219	product specification	-	74LVT574 v.1
74LVT574 v.1	19951114	product specification	-	-

15. Legal information

15.1 Data sheet status

Document status[1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions"
- [3] The product status of device(s) described in this document may have changed since this document was published and may differ in case of multiple devices. The latest product status information is available on the Internet at URL http://www.nxp.com.

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74LVT_LVTH574

74LVT574; 74LVTH574

3.3 V octal D-type flip-flop; 3-state

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